Physics-Informed Operator Learning for Design-of-Experiments Applied to Lithium-Ion-Batteries

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I. Introduction

Motivation:

- Difficulties in parameter identifiability of Lithium-Ion-Battery (LIB) surrogate models cause high expenses in time and cost for R&D and pose a challenge for on-board estimation of State-of-Health (SOH) or specific degradation modes.
- Design-of-Experiment (DoE) methodologies can improve parameter identifiability by maximizing the information provided by measurements, which can, e.g., be quantified via Fisher-Information-Matrices (FIMs).

Goals:

- Evaluate Physics-Informed Deep Operator Networks as parametrized surrogate models for varying current profiles and diffusivity parameters.
- Demonstrate their accuracy and inference speed in approximating FIMs.

II. Methodology

Single-Particle-Model (SPM):

 Partial Differential Equation (PDE) to describe Li-concentration $c_i(r,t)$ in two spherically symmetric particles for anode (j=n) and cathode (j=p):

$$\frac{\partial c_j(r,t)}{\partial t} = \frac{\mathbf{D}_j}{r^2} \frac{\partial}{\partial r} \left(r^2 \frac{\partial c_j(r,t)}{\partial r} \right).$$

• Initial (IC) and Boundary Conditions (BCs):

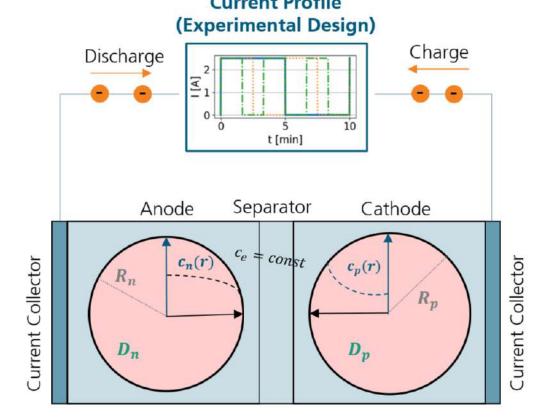


Figure 1: Single-Particle-Model.

$$c_j(r,0) = c_j^0, \frac{\partial c_j(0,t)}{\partial r} = 0, \qquad \frac{\partial c_j(R_j,t)}{\partial r} = \pm \frac{I(t)}{AL_jFD_ja_j}.$$

Voltage response via

$$V(t) = U_p^{\text{OCP}}(c_p(R_p, t)) - U_n^{\text{OCP}}(c_n(R_n, t)) + \eta_r(t).$$

• Open-circuit-potentials $U_i^{ ext{OCP}}$, overpotential η_r and further parameters are assumed from a cylindrical 21700 cell (LGM50) characterized by Chen et al. [1].

Physics-Informed Deep Operator Network (PI-DeepONet):

- Data-free training via minimization of PDE, IC and BC residuals.
- Branch: Encoding discretized current profiles I(t) describing three use cases: Constant current (CC), Gaussian Random Fields (GRF) and pulse profiles.
- Trunk: Encoding spatio-temporal domain (r,t) and diffusivity domain $(D_n, D_p) \in [10^{-15}, 10^{-13}]^2$.

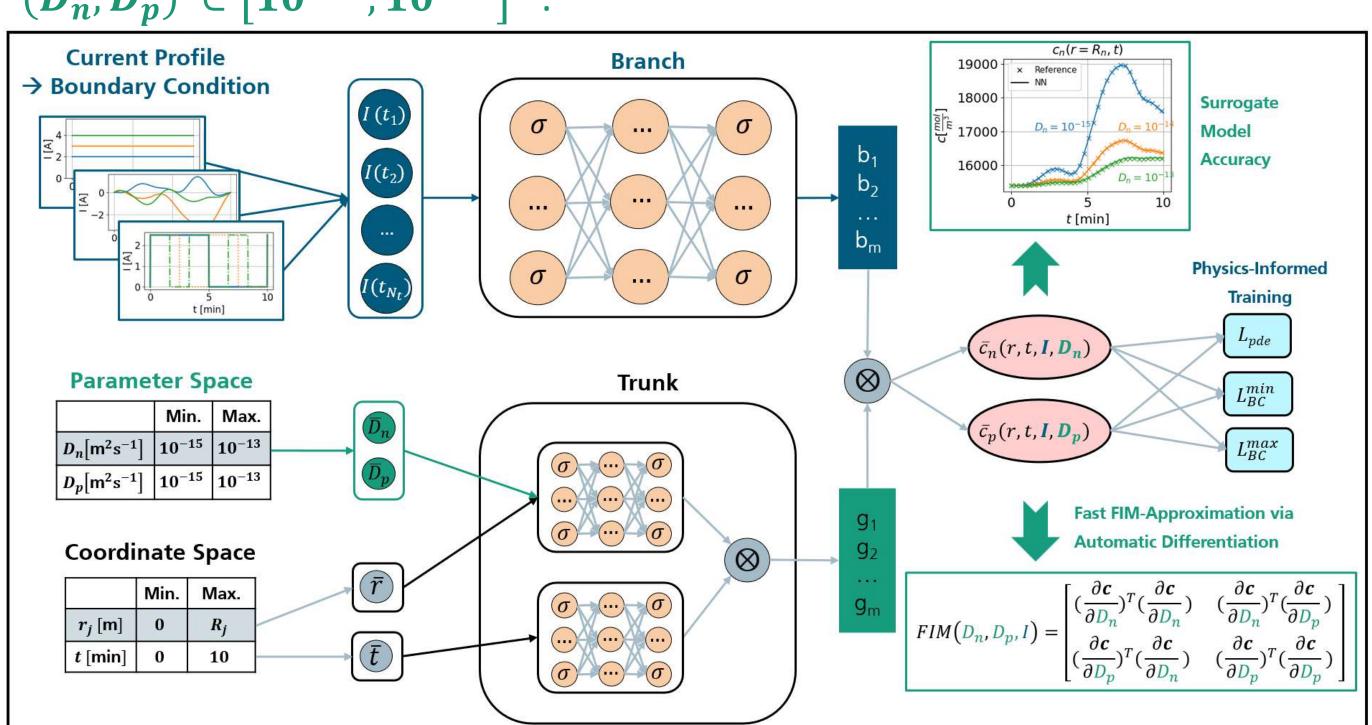


Figure 2: Parametrized PI-DeepONet for prediction of SPM solutions for varying current profiles (branch) and diffusivities (trunk).

DoE Framework:

The FIM quantifies the information provided by a given experimental design I(t), e.g., for identifying parameters (D_n, D_p) from the model response

$$\boldsymbol{c} = \left(c_{n}(R_{n}, t^{k}, D_{n}, I), c_{p}(R_{p}, t^{k}, D_{p}, I)\right), \qquad k = 0, \dots, 600,$$

$$\boldsymbol{FIM}(\boldsymbol{D_{n}}, \boldsymbol{D_{p}}, \boldsymbol{I}) = \begin{bmatrix} (\frac{\partial c}{\partial D_{n}})^{T} (\frac{\partial c}{\partial D_{n}}) & (\frac{\partial c}{\partial D_{n}})^{T} (\frac{\partial c}{\partial D_{p}}) \\ (\frac{\partial c}{\partial D_{p}})^{T} (\frac{\partial c}{\partial D_{n}}) & (\frac{\partial c}{\partial D_{p}})^{T} (\frac{\partial c}{\partial D_{p}}) \end{bmatrix}.$$

The scalar "D-optimality" can be maximized for optimal experimental design:

$$\mathcal{D}^{\text{opt}}(\boldsymbol{D}_n, \boldsymbol{D}_p, \boldsymbol{I}) = \log \left(\det \left(\text{FIM}(\boldsymbol{D}_n, \boldsymbol{D}_p, \boldsymbol{I}) \right) \right).$$

III. Results

Surrogate model accuracy:

• Comparison with reference solution from *PyBaMM* [2] via Normalized-Mean-Absolute-Percentage-Error at particle surfaces and Root-Mean-Squared-Error on the resulting voltage response ($N_t = 101$):

$$NMAPE^{surf} = \frac{1}{2} \sum_{j \in \{n,p\}} \frac{1}{N_t} \sum_{i=0}^{N_t} \frac{|c_j^{NN}(R_j, t_i) - c_j^{ref}(R_j, t_i)|}{\max(c_j^{ref}(R_j, t)) - \min(c_j^{ref}(R_j, t))} \cdot 100\%,$$

$$RMSE = \sqrt{\frac{1}{N_t} \sum_{i=0}^{N_t} |V(c^{NN}, t_i) - V(c^{ref}, t_i)|^2}.$$

Figure 3. Accuracy evolution during training of PI-DeepONets for different use cases averaged over multiple current profiles I(t) in each use case, cf. Fig. 2 – top left. Training times are measured on a NVIDIA A100 GPU.

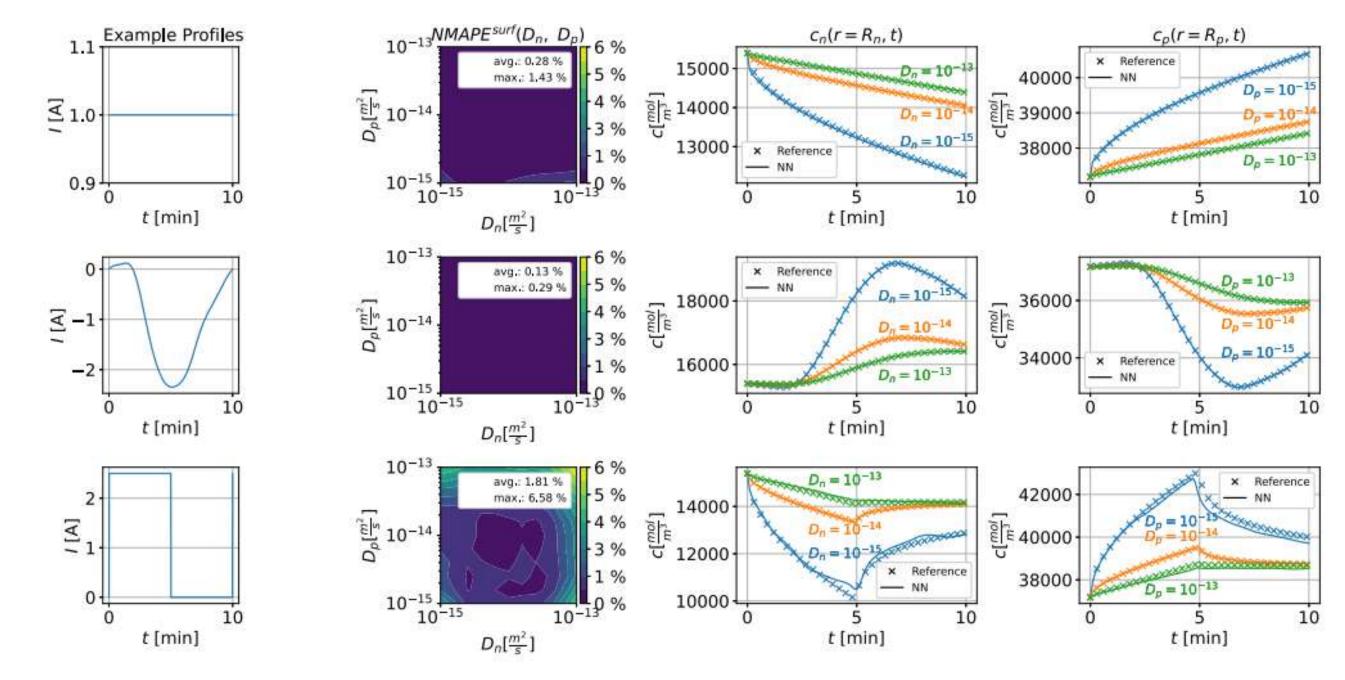


Figure 4. Surrogate model accuracy at particle surfaces for three exemplary profiles and varying diffusivities $(D_n, D_p) \in \{10^{-15}, 10^{-14}, 10^{-13}\}.$

Accuracy for DoE based on FIM-Analysis:

D-optimalities are approximated accurately and more efficiently via AD on the trained PI-DeepONet compared to the reference based on *PyBaMM* [2]:

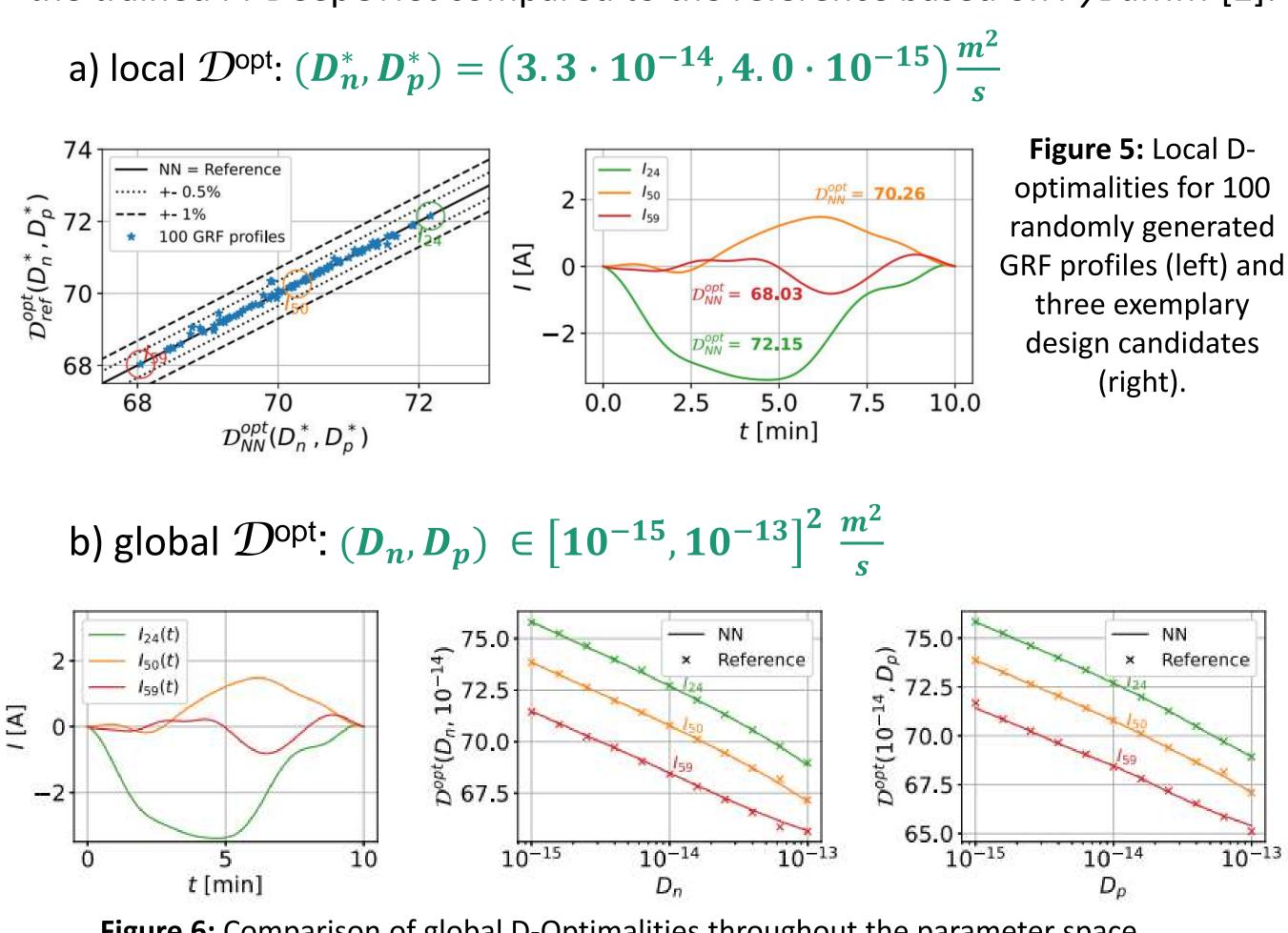


Figure 6: Comparison of global D-Optimalities throughout the parameter space.

Conclusion:

Parametrized PI-DeepONets can be accurate and fast surrogate models with inference times in the order of milliseconds and offer further potential for DoE methodologies based on Fisher-Information. See [3] for more insights and implementation details.

IV. Outlook

- Integration of more realistic, high-frequency current profiles, variation of further (aging) parameters and a voltage-based FIM approximation.
- Demonstration of improved parameter and state estimation procedures based on PI-DeepONets and realistic application-specific voltage data.

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References:

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